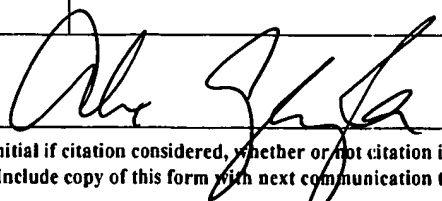


<div>U.S. PATENT & TRADEMARK OFFICE INFORMATION DISCLOSURE CITATION (Use several sheets if necessary) OCT 29 2004</div>				Docket Number (Optional) P0387		Application Number 10/789,336		
				Applicant(s) Erwan Le Roy et al				
				Filing Date 02/27/2004		Group Art Unit na		
U.S. PATENT DOCUMENTS								
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
AC	1	5,948,217	09/07/1999	Winer et al	204	192.34	12/20/1996	
U.S. PATENT APPLICATION PUBLICATIONS								
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
FOREIGN PATENT DOCUMENTS								
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)								
AC	1	E.L. Cole, "Beam-Based Localization Techniques for IC Failure Analysis", Microelectronic Failure Analysis, Desk Reference 4th ed., R. Ross, C. Boit, D. Staab, editors (2001) ASM International Materials Park, OH, pp. 136-137						
AC	2	V.S. Aliev and V.N. Kruchinin, "Development of Si(100) Surface Roughness at the Initial Stage of Etching in F2 and XeF2 Gases: Ellipsometric Study", Surface Sciencet 442 (1999), pp 206-214						
EXAMINER <i>Ally G. [Signature]</i>				DATE CONSIDERED <i>6/5/05</i>				
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

<div data-bbox="113 136 332 367" data-label="Image"> </div> <div data-bbox="186 147 682 220" data-label="Section-Header"> <p>INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)</p> </div>		Docket Number (Optional) P0387	Application Number 10/789,336
		Applicant(s) Erwan Le Roy et al	
		Filing Date 02/27/2004	Group Art Unit na
<div data-bbox="121 283 235 441" data-label="Text"> <p>EXAMINER INITIAL AC</p> </div> <div data-bbox="373 283 1055 325" data-label="Section-Header"> <p>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</p> </div> <div data-bbox="308 325 1469 409" data-label="Text"> <p>E. I. Cole Jr., C. R. Bagnell, Jr., B. Davies, A. Neacsu, W. Oxford, S. Roy, and R. H. Propst, "A Novel Method for Depth Profiling and Imaging of Semiconductor Devices Using Capacitive Coupling Voltage Contrast", J. Appl. Phys, 62(12), 15 December 1987, pp 4909-4915</p> </div>			
<div data-bbox="105 462 1477 1795" data-label="Image"> </div>			
EXAMINER 		DATE CONSIDERED 6/5/05	

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.